

# MSKSEMI 美森科

SEMICONDUCTOR



ESD



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GDT



PLED

## AONR21321-MS

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Product specification

## Description

The AONR21321-MS uses advanced trench technology excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a load switch or in PWM applications.

## Features

$V_{DS} = -30V, I_D = -50A$

$R_{DS(ON)} < 25m\Omega @ V_{GS} = -4.5V$

$R_{DS(ON)} < 15m\Omega @ V_{GS} = -10V$

High Power and current handling capability

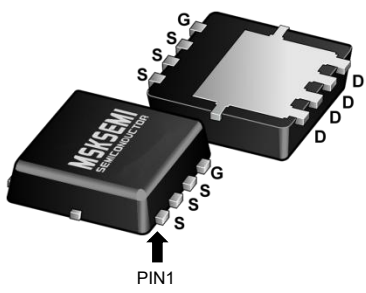
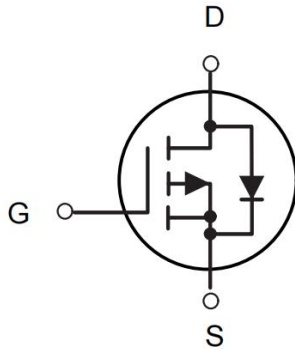

Lead free product is acquired

Surface mount package

## Application

- PWM applications
- Load switch
- Power management

## Reference News

PACKAGE OUTLINE	P-Channel MOSFET	Marking
 <p>DFN5X6-8L</p>		

## Absolute Maximum Ratings (TA=25°C unless otherwise noted)

Symbol	Parameter	Limit	Unit
V <sub>DS</sub>	Drain-Source Voltage	-30	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
I <sub>D</sub>	Drain Current-Continuous (T <sub>c</sub> =25 °C)	-50	A
	Drain Current-Continuous (T <sub>c</sub> =100 °C)	-24	
I <sub>DM</sub>	Drain Current-Pulsed (Note 1)	-80	A
P <sub>D</sub>	Maximum Power Dissipation (T <sub>c</sub> =25 °C)	3	W
	Maximum Power Dissipation (T <sub>c</sub> =100 °C)	1.3	
EAS	Single pulse avalanche energy (Note 5)	231	mJ
T <sub>J</sub> , T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 To 150	°C
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient (Note 2)	41.67	°C/ W

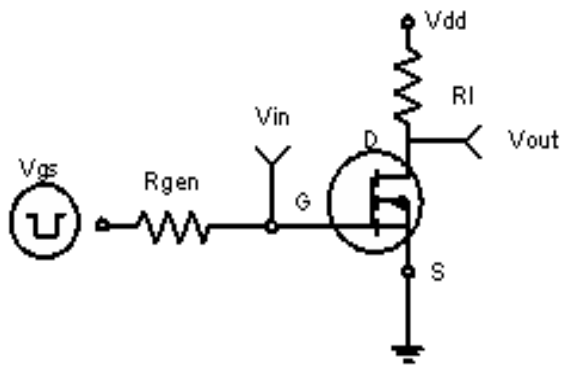
**Electrical Characteristics (TA=25°C unless otherwise noted)**

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Drain- Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =-250μA	-30	-33	-	V
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V	-	-	-1	μA
Gate- Body Leakage Current	IGSS	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
Gate Threshold Voltage	VGS(th)	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA	-1	-1.5	-3	V
Drain- Source On- State Resistance	RDS(ON)	V <sub>GS</sub> =-10V, I <sub>D</sub> =-10A	-	9	15	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-7A	-	18	25	mΩ
Forward Transconductance	gFS	V <sub>DS</sub> =-10V, I <sub>D</sub> =-10A	-	20	-	S
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =-15V, V <sub>GS</sub> =0V, F=1.0MHz	-	1750	-	PF
Output Capacitance	C <sub>oss</sub>		-	215	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	180	-	PF
Turn-on Delay Time	td(on)	V <sub>DD</sub> =-15V, I <sub>D</sub> =-10A, V <sub>GS</sub> =-10V, R <sub>GEN</sub> =1 Ω	-	9	-	nS
Turn-on Rise Time	t <sub>r</sub>		-	8	-	nS
Turn-Off Delay Time	td(off)		-	28	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	10	-	nS
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =-15V, I <sub>D</sub> =-10A, V <sub>GS</sub> =-10V	-	24	-	nC
Gate- Source Charge	Q <sub>gs</sub>		-	3.5	-	nC
Gate- Drain Charge	Q <sub>gd</sub>		-	6	-	nC
Diode Forward Current (Note 2)	I <sub>S</sub>		-	-	-12	A
Diode Forward Voltage (Note 3)	VSD	V <sub>GS</sub> =0V, I <sub>S</sub> =-12A	-	-	-1.2	V

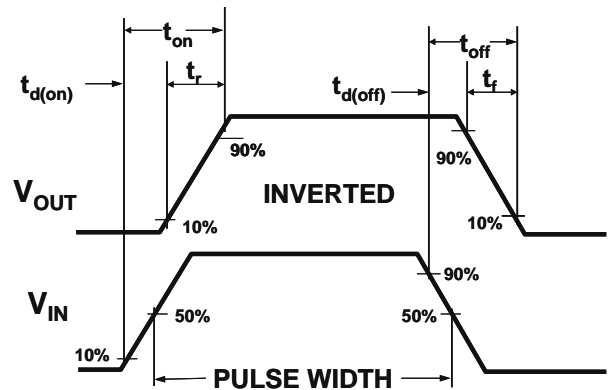
**Notes:**

1. Repetitive Rating: Pulse width limited by maximum junction temperature .
2. Surface Mounted on FR4 Board, t ≤ 10 sec .
3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2% .
4. Guaranteed by design, not subject to production
5. E<sub>AS</sub> condition: T<sub>j</sub>=25C, V<sub>DD</sub>=- 15V, V<sub>G</sub>=10V, L=0 .5mH, R<sub>g</sub>=25Ω, I<sub>AS</sub>=-34A

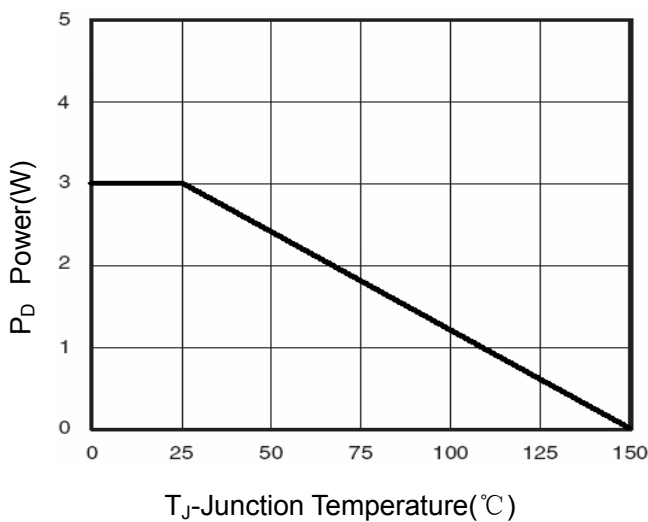
**Typical Electrical and Thermal Characteristics**



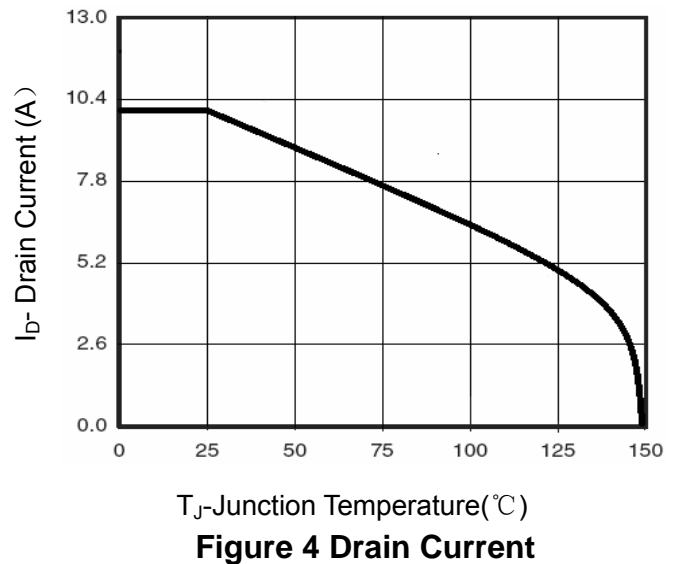
**Figure 1: Switching Test Circuit**



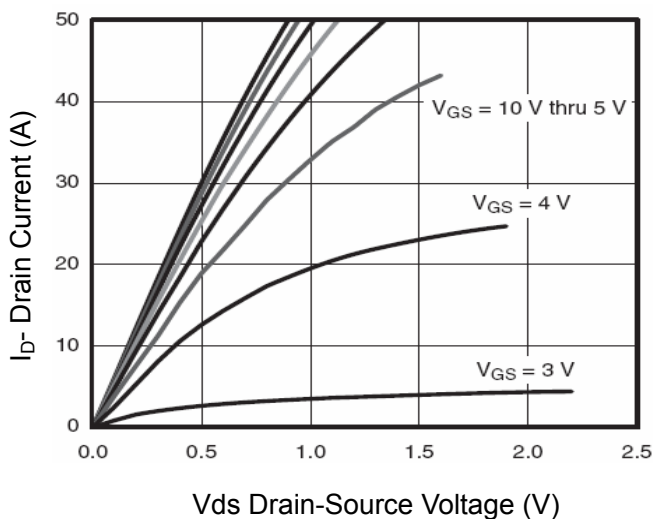
**Figure 2: Switching Waveforms**



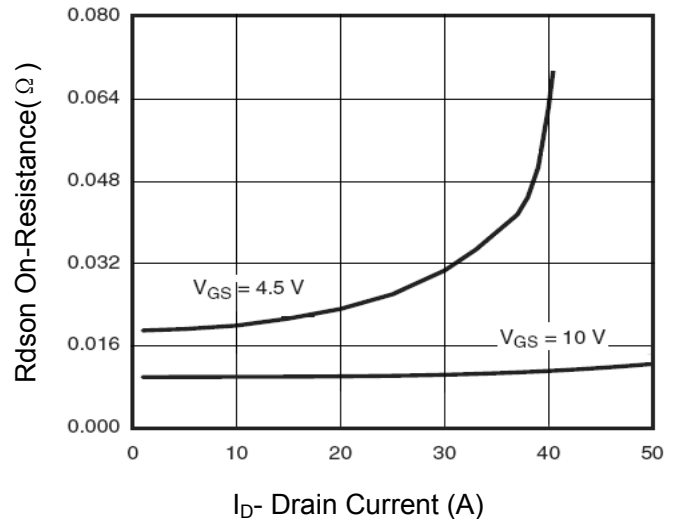
**Figure 3 Power Dissipation**



**Figure 4 Drain Current**

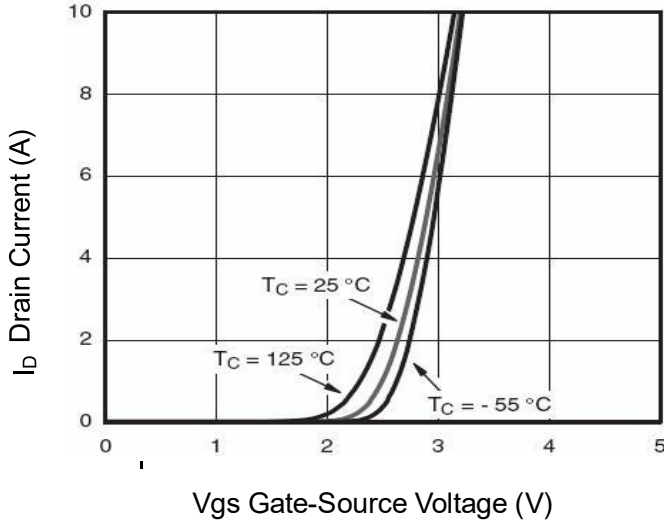


**Figure 5 Output Characteristics**

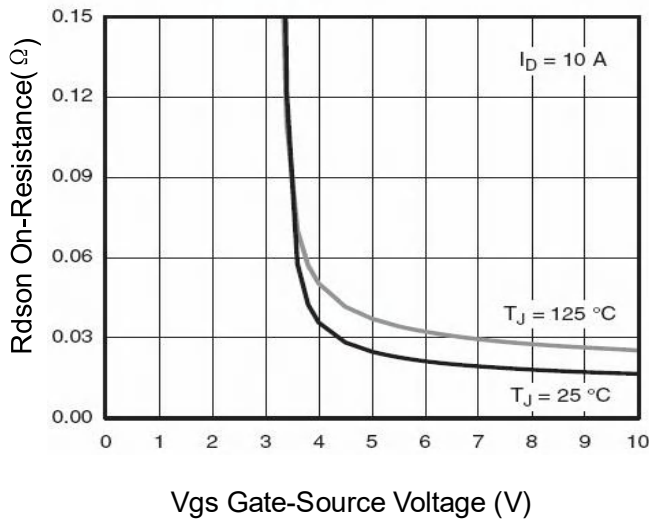


**Figure 6 Drain-Source On-Resistance**

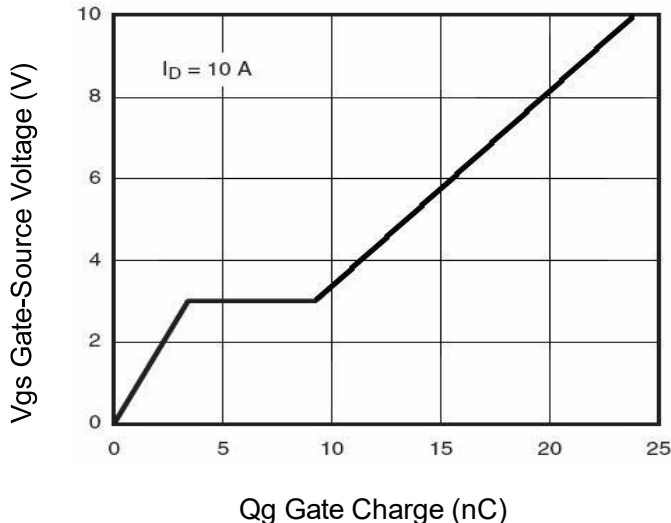
**Figure 5 Output Characteristics**



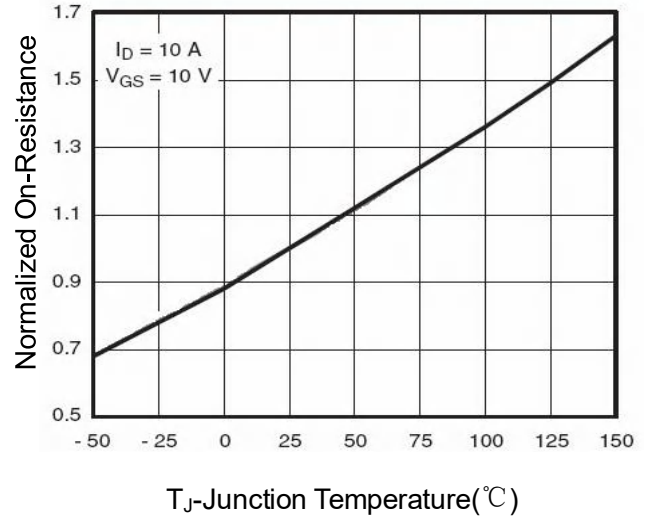
**Figure 7 Transfer Characteristics**



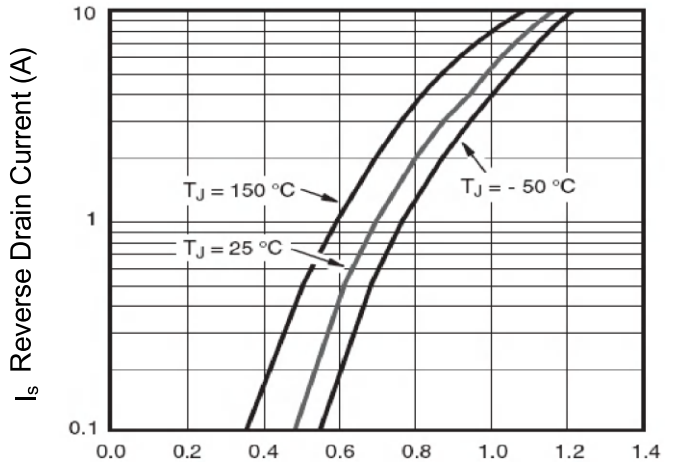
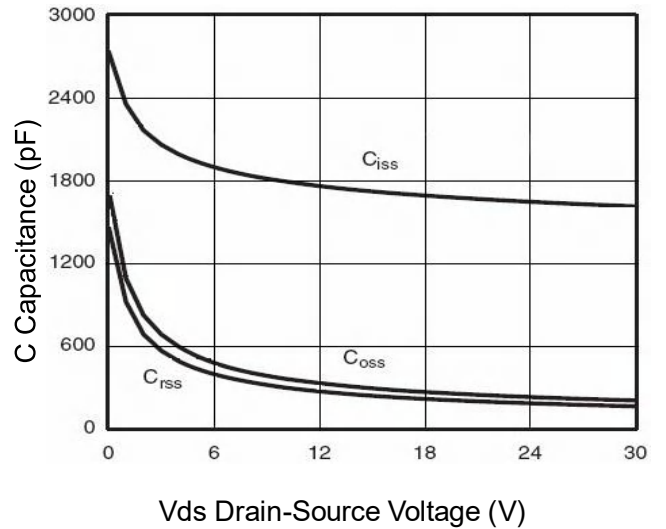
**Figure 9 Rdson vs Vgs**



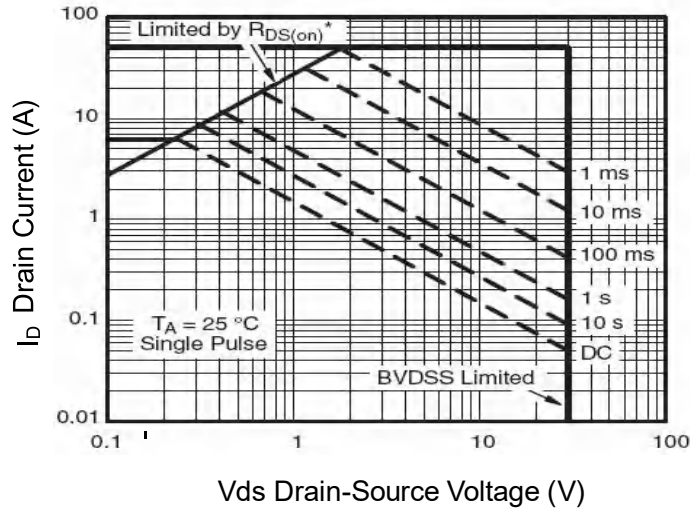
**Figure 11 Gate Charge**



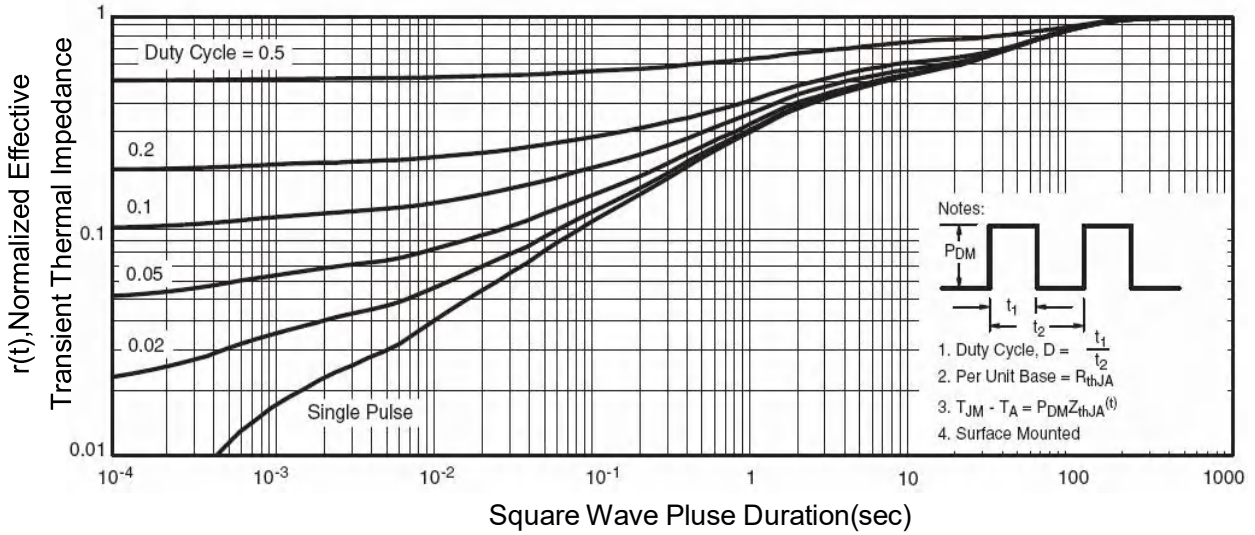
**Figure 10 Capacitance vs Vds**



**Figure 12 Source- Drain Diode Forward**

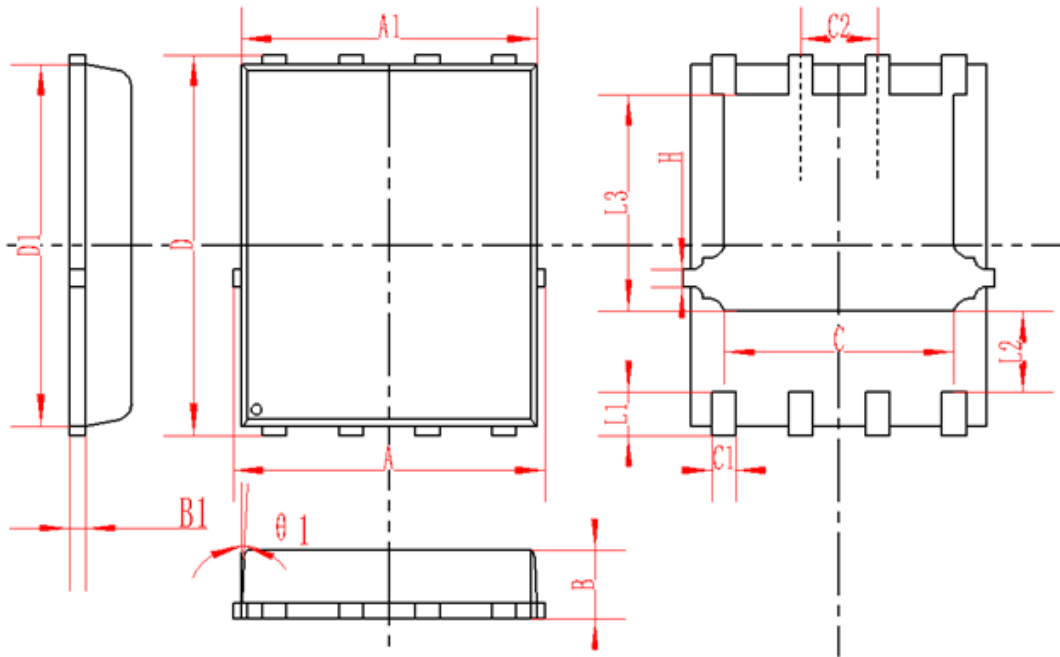


**Figure 13 Safe Operation Area**



**Figure 14 Normalized Maximum Transient Thermal Impedance**

**DFN5X6-8L Package Information**



SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
A	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
B	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF			0.010REF		
C	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2	1.27TYP			0.5TYP		
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
H	0.24	0.25	0.26	0.009	0.010	0.010

**REEL SPECIFICATION**

P/N	PKG	QTY
AONR21321-MS	DFN5X6-8L	5000

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